

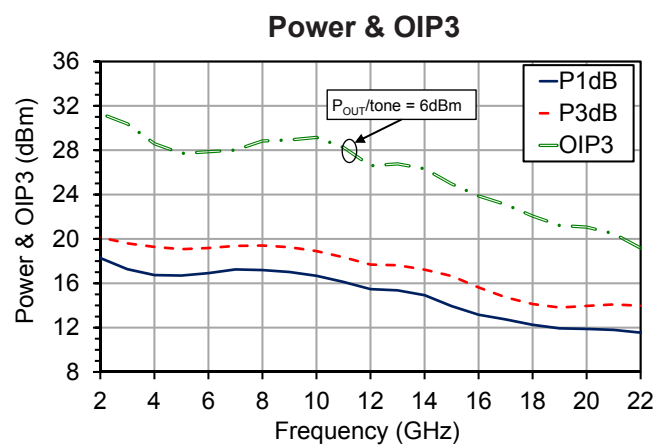
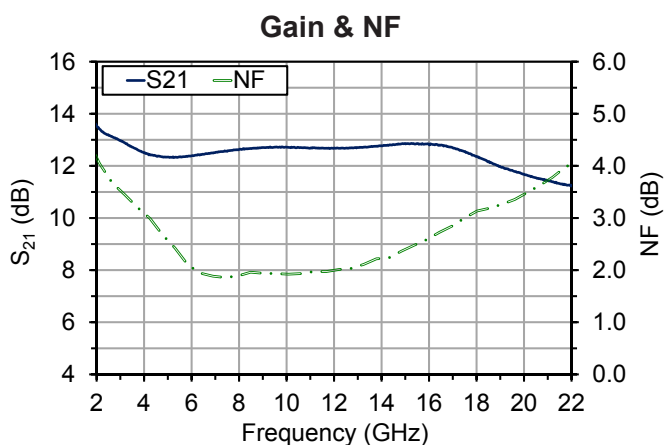
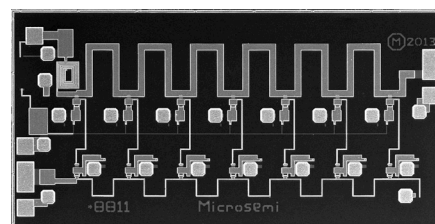
## 2-20GHz, 12.5dB Gain Low-Noise Wideband Distributed Amplifier

### Features

- >16.5dBm  $P_{1dB}$  with 1.9dB NF and 12.5dB gain at 10GHz
- <2dB NF from 6-12GHz
- Single supply voltage of +8V @ 50mA
- Input and Output matched to 50 $\Omega$
- 1.5mm x 2.82mm x 0.1mm die size

### Applications

- Instrumentation
- Electronic warfare
- Microwave communications
- Radar



**Typical Performance (CW, Typical Device, RF Probe):**  $T_A = 25^\circ\text{C}$ ,  $V_{DD} = 8\text{V}$

Parameter	Min	Typ	Max	Units
Frequency	2	-	22	GHz
Small Signal Gain	11.3	-	13.5	dB
Noise Figure	1.9	2.5	4.0	dB
Output Power, $P_{1dB}$	12	14	18	dBm
Output Power, $P_{3dB}$	14	18	20	dBm
Output IP3	19	26	31	dBm
Drain Current		50		mA

**Table 1: Absolute Maximum Ratings, Not Simultaneous**

Parameter	Rating	Units
Drain Voltage ( $V_D$ )	+9	V
Input Power ( $P_{IN}$ )	24	dBm
Channel Temperature ( $T_C$ )	150 <sup>1</sup>	°C
Operating Ambient Temperature ( $T_A$ )	-55 to +85	°C
Storage Temperature	-65 to +150	°C
Thermal Resistance, Channel to Die Backside	40	°C/W

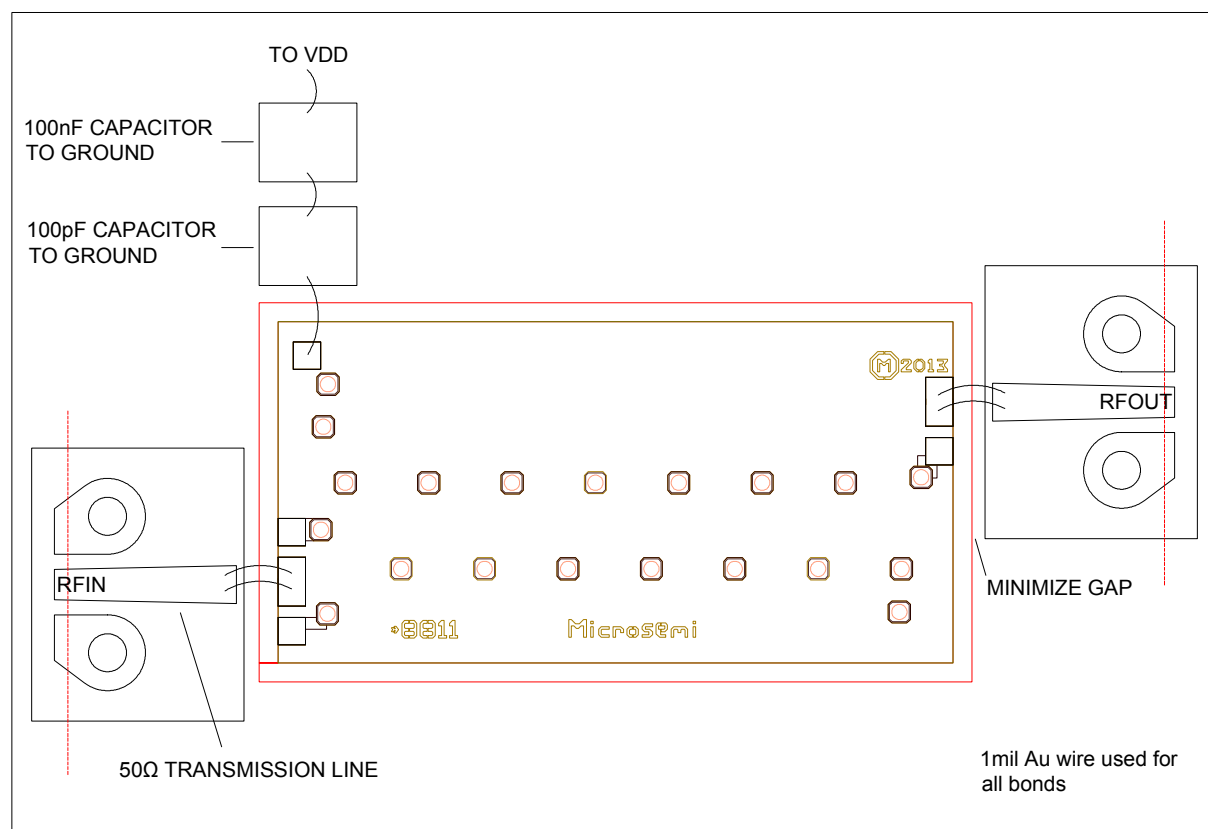
<sup>1</sup> MTTF > 10<sup>8</sup> hours at  $T_C = 150^\circ\text{C}$ 


Caution, ESD  
Sensitive Device

**Table 2: Specifications (CW, 100% Test):  $T_A = 25^\circ\text{C}$ ,  $V_{DD} = 8\text{V}$** 

Parameter		Min	Max	Units
$I_{DD}$	-	-	105	mA
Small Signal Gain	20GHz	9.5	-	dB
Output Power, $P_{1dB}$	20GHz	9.0	-	dBm

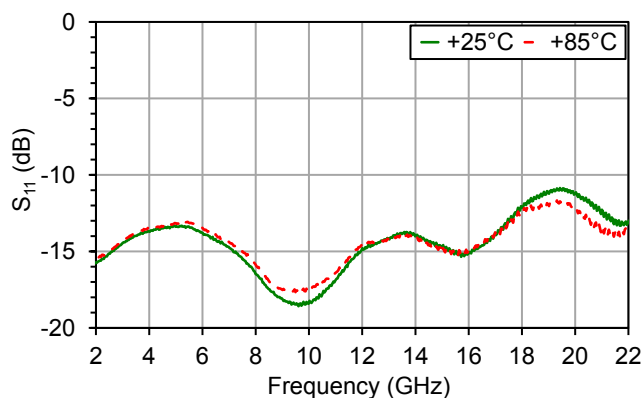
## RF Probe Measurement Set-Up With Reference Planes<sup>2</sup>


<sup>2</sup> Reference planes are the same for S-parameter files downloadable on [www.microsemi.com/mmics](http://www.microsemi.com/mmics)

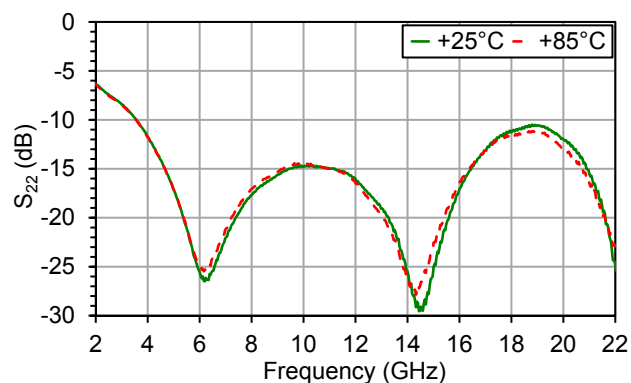
## Typical Performance, RF Probe

$V_{DD} = 8V$ ,  $I_{DD} = 50mA$ ,  $T_A = 25^\circ C$  unless otherwise noted

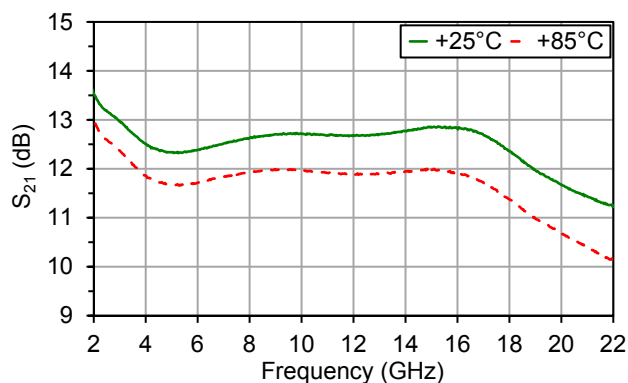
**$S_{11}$  Over Temperature**



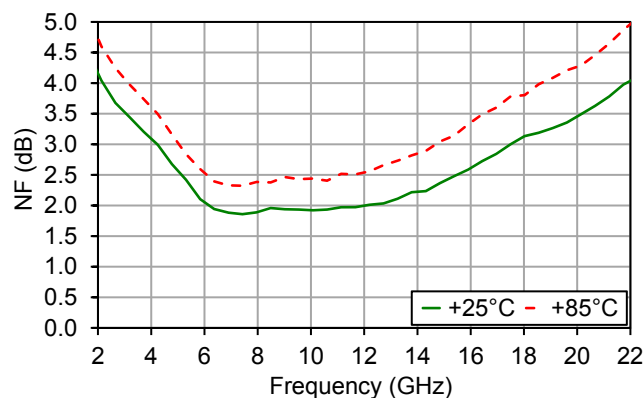
**$S_{22}$  Over Temperature**



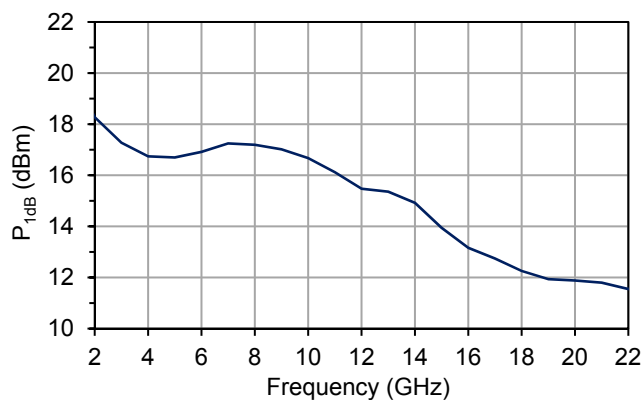
**$S_{21}$  Over Temperature**



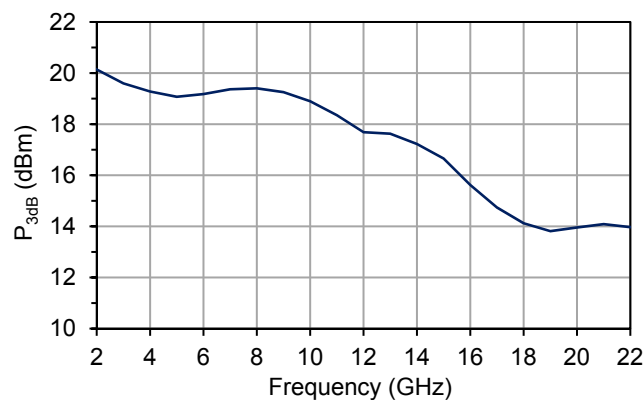
**NF Over Temperature**



**$P_{1dB}$  Over Frequency**



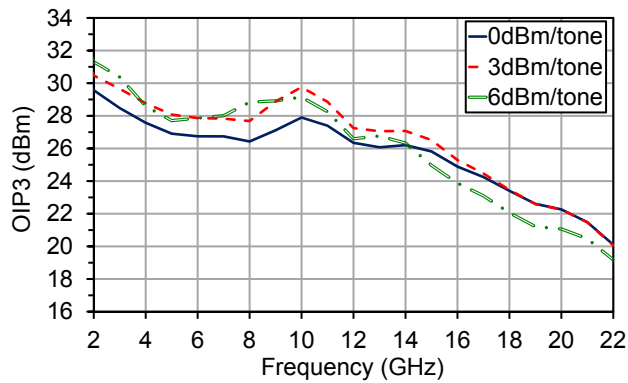
**$P_{3dB}$  Over Frequency**



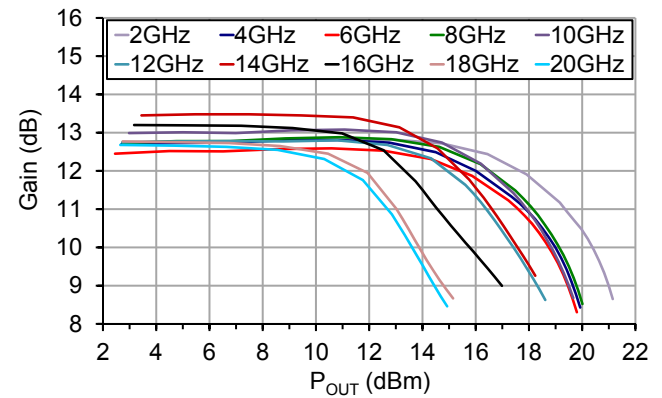
## Typical Performance, RF Probe

$V_{DD} = 8V$ ,  $I_{DD} = 50mA$ ,  $T_A = 25^\circ C$  unless otherwise noted

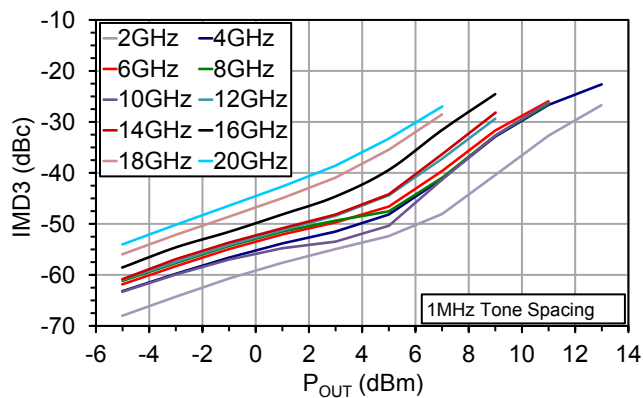
**OIP3 Over  $P_{OUT}$**



**Power Sweep**

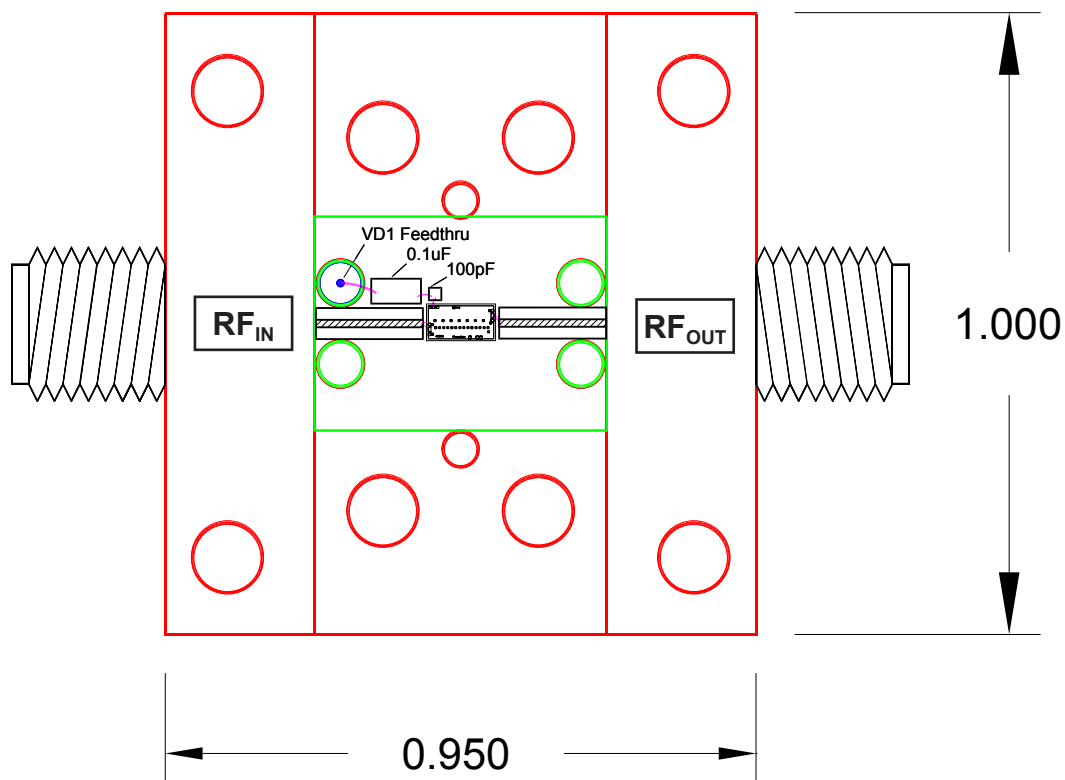


**IMD3 Sweep**



## Connectorized Test Fixture

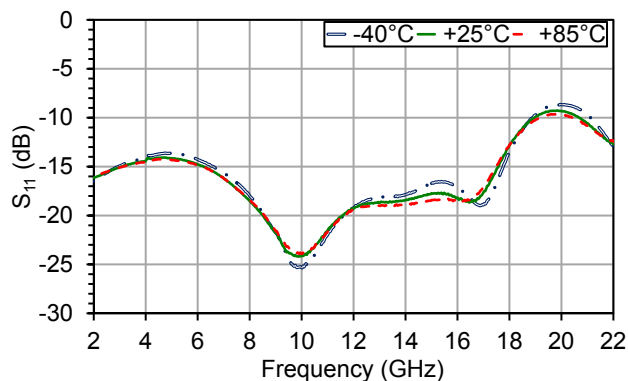
With SMK 2.92mm Connectors



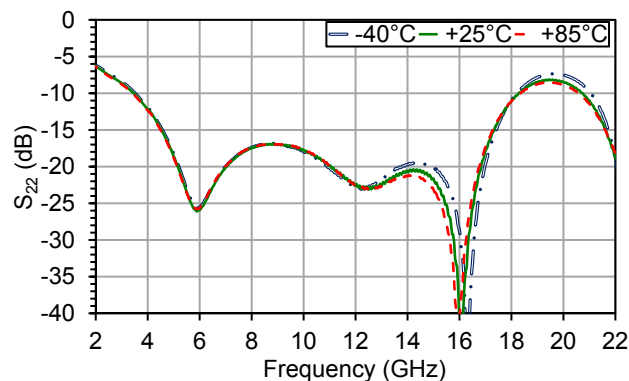
## Typical Performance, Connectorized Test Fixture

$V_{DD} = 8V$ ,  $I_{DD} = 50mA$ ,  $T_A = 25^\circ C$  unless otherwise noted

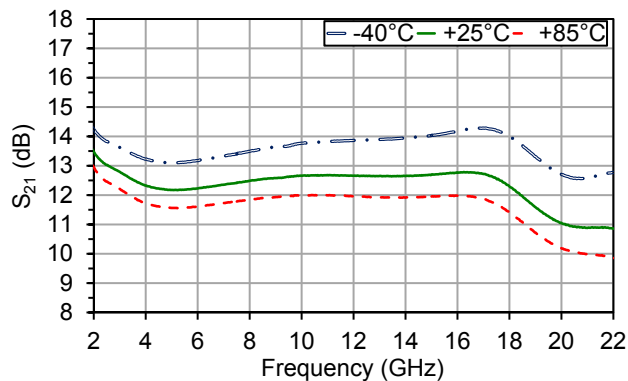
**$S_{11}$  Over Temperature**



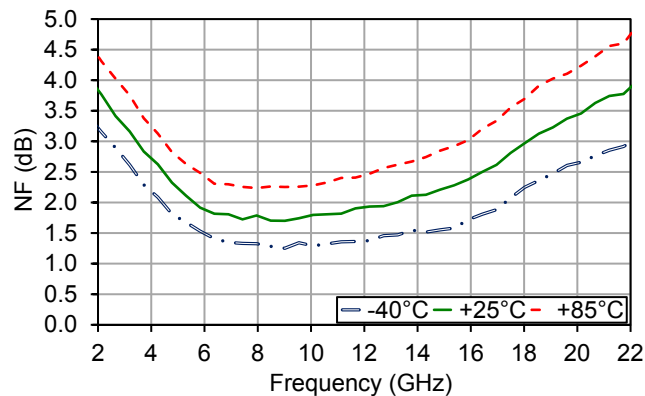
**$S_{22}$  Over Temperature**



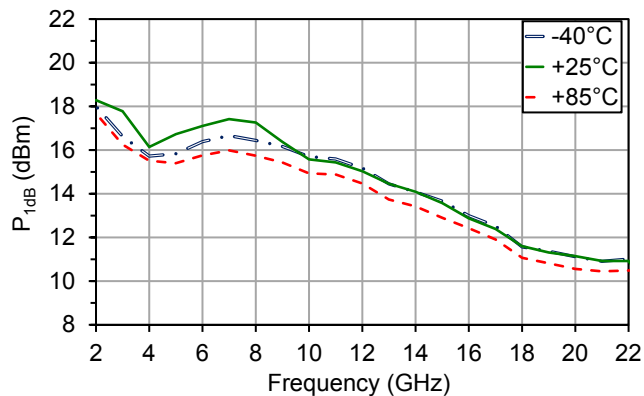
**$S_{21}$  Over Temperature**



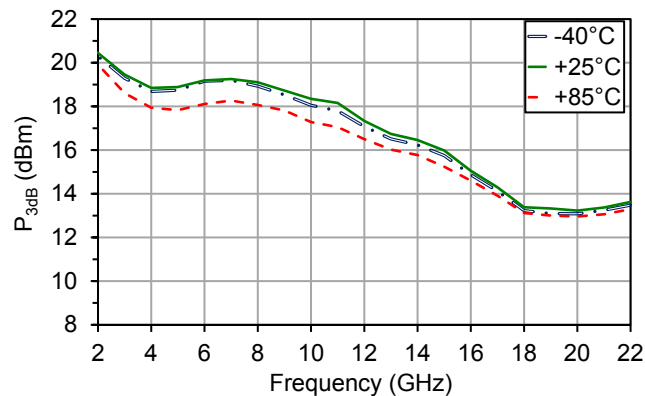
**NF Over Temperature**



**$P_{1dB}$  Over Temperature**



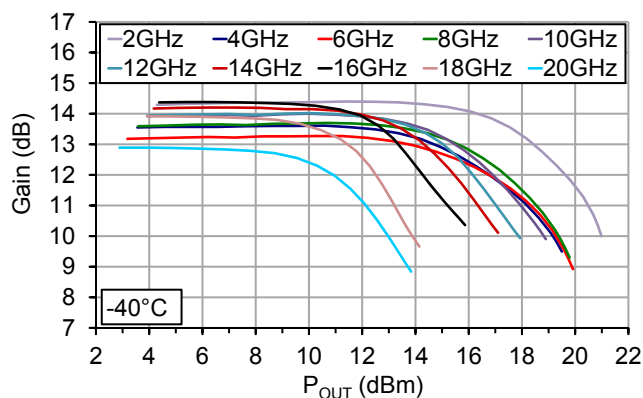
**$P_{3dB}$  Over Temperature**



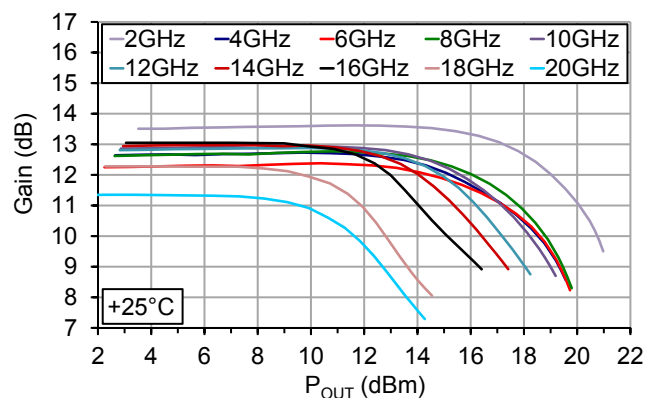
## Typical Performance, Connectorized Test Fixture

$V_{DD} = 8V$ ,  $I_{DD} = 50mA$ ,  $T_A = 25^\circ C$  unless otherwise noted

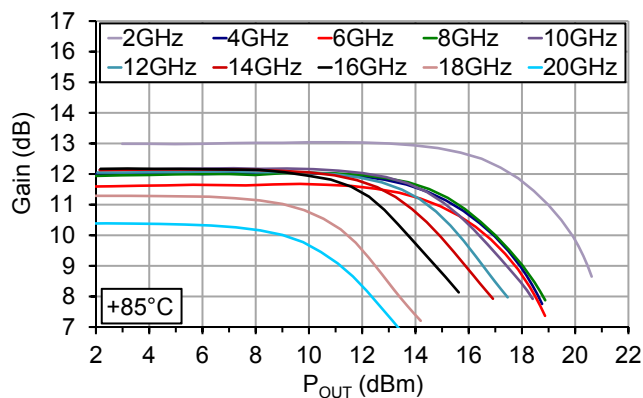
**Power Sweep,  $-40^\circ C$**



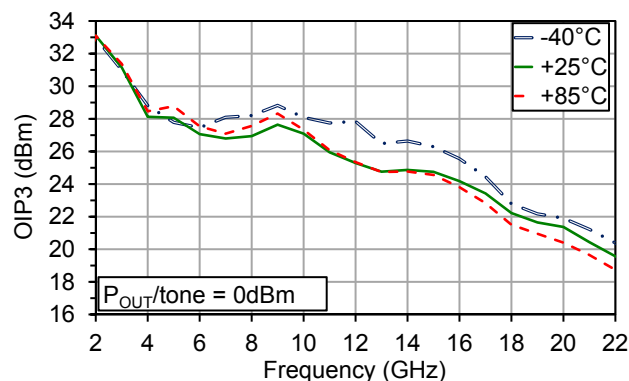
**Power Sweep,  $+25^\circ C$**



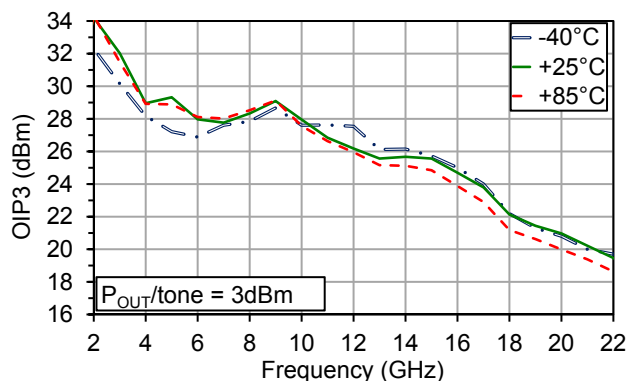
**Power Sweep,  $+85^\circ C$**



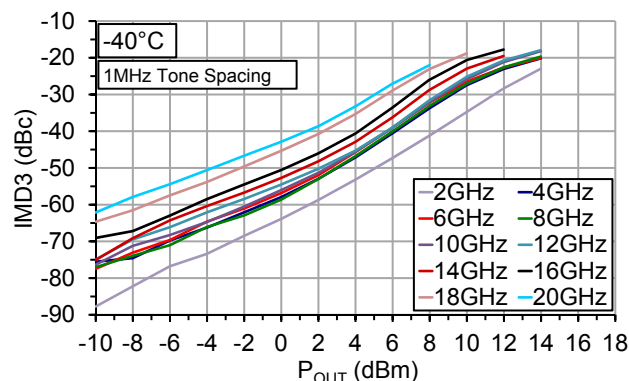
**OIP3, 0dBm/tone**



**OIP3, 3dBm/tone**



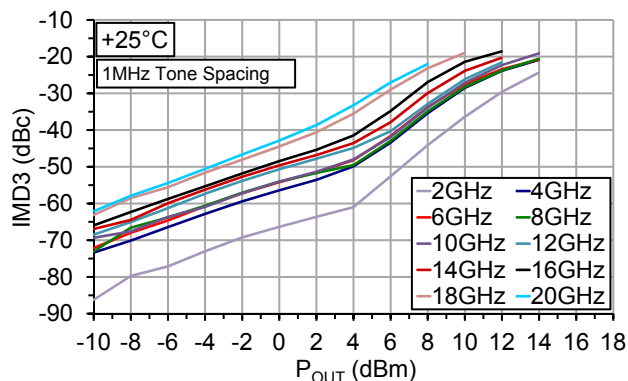
**IMD3 Sweep,  $-40^\circ C$**



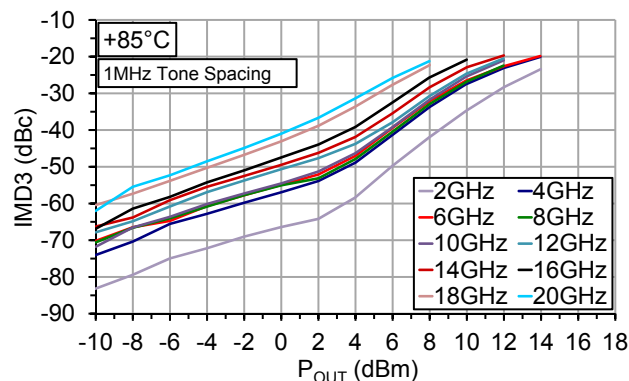
## Typical Performance, Connectorized Test Fixture

$V_{DD} = 8V$ ,  $I_{DD} = 50mA$ ,  $T_A = 25^\circ C$  unless otherwise noted

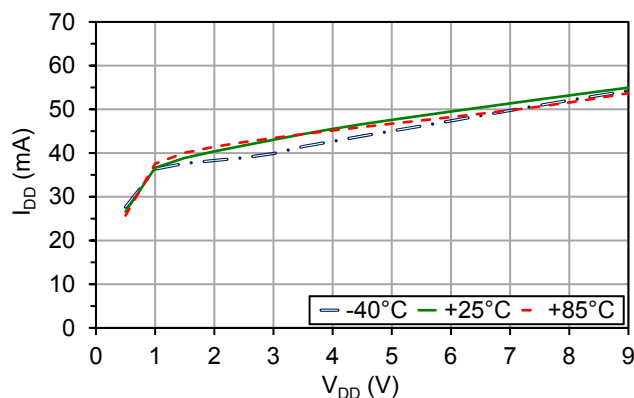
IMD3 Sweep,  $+25^\circ C$ , 1MHz Tone Spacing



IMD3 Sweep,  $+85^\circ C$ , 1MHz Tone Spacing



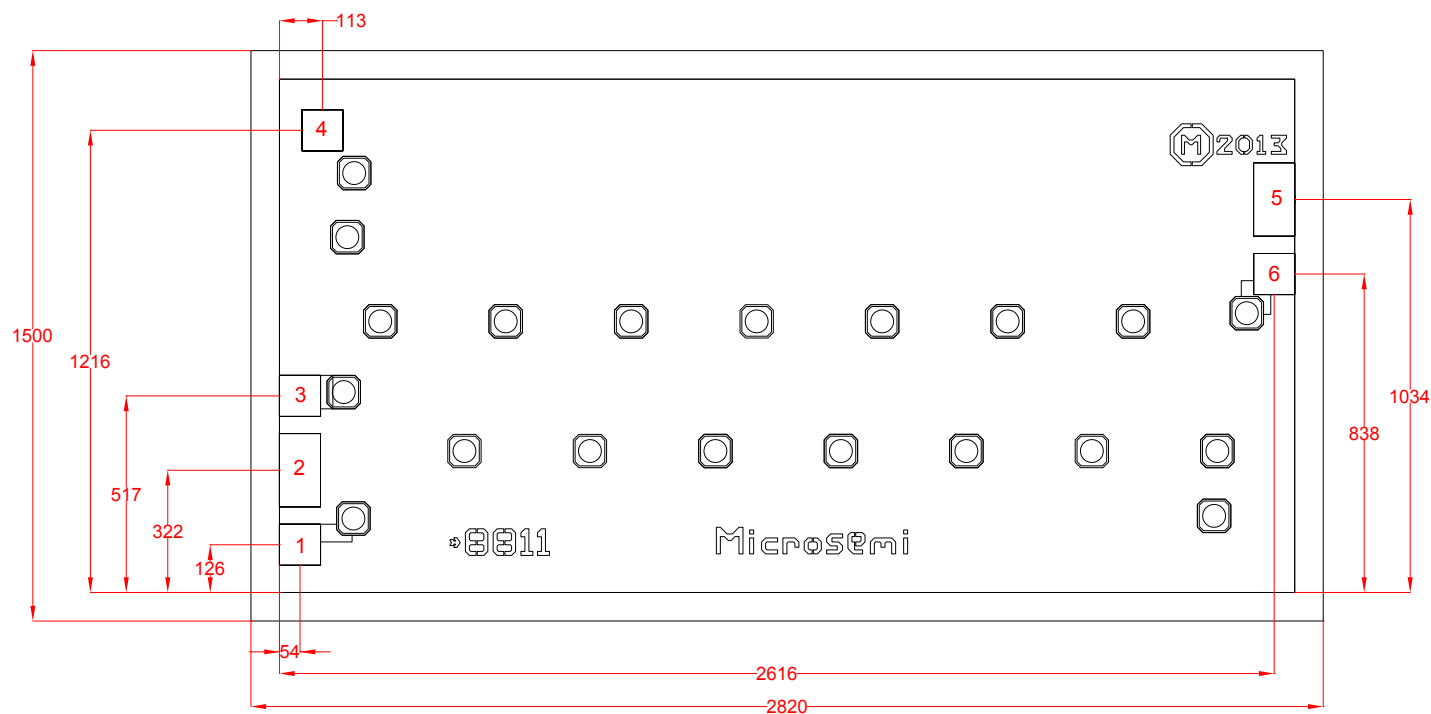
DC





### Chip layout showing pad locations.

All dimensions are in microns. Die thickness is 100 microns. Backside metal is gold, bond pad metal is gold.  
Refer to Die Handling Application Note MM-APP-0001 (visit [www.microsemi.com/mmics](http://www.microsemi.com/mmics)).



**Table 3: Pad Descriptions**

Pad #	Description	Pad Dimensions ( $\mu\text{m}$ )
1, 3, 6	Ground	100 x 100
2	$\text{RF}_{\text{IN}}$ , AC Coupled	100 x 190
5	$\text{RF}_{\text{OUT}}$ , AC Coupled	100 x 190
4	$V_{\text{DD}}$	100 x 100

### Biasing

MMA003AA is a self-biased device with single positive supply. Apply  $V_{\text{DD}}$  to pad 4.

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